



National Institute of Standards & Technology

Certificate of Analysis

Standard Reference Material[®] 3192

Aqueous Electrolytic Conductivity

Lot No. 031121

This Standard Reference Material (SRM) is intended primarily for use in electrolytic conductivity measurement as a calibration standard or control sample. As a calibration standard, it can be used to determine the conductivity cell constant. One unit of SRM 3192 consists of eight glass ampoules, each containing 50 mL of solution. The solution was prepared by dissolving reagent grade potassium chloride (KCl) in deionized water in equilibrium with atmospheric carbon dioxide.

SRM 3192 was prepared gravimetrically using deionized water that was filtered through a 0.22 μm filter. The initial electrolytic conductivity of this water was less than 0.2 $\mu\text{S}/\text{cm}$. The solution was dispensed into borosilicate glass (Wheaton 33[®])¹ ampoules. The certified electrolytic conductivity and its uncertainty given below were established through determinations with a conductivity cell immersed in a constant temperature oil bath and using a Jones bridge with a null detector. This cell is calibrated with primary standard conductivity solutions [1]. The conductivity bridge and electronics are described in reference 2.

The certified value given below is based on equilibrium conditions, and the solution should **NOT** be degassed before use.

Electrolytic Conductivity at 25.000 °C: 497.11 $\mu\text{S}/\text{cm}$ \pm 0.33 $\mu\text{S}/\text{cm}$

The uncertainty in the certified value, $U = 0.33 \mu\text{S}/\text{cm}$, is calculated as

$$U = 2.0u_c$$

where u_c is the *combined standard uncertainty* calculated according to the ISO and NIST Guides [3]. The value of u_c is intended to represent, at the level of one standard deviation, the combined effect of uncertainty components associated with the random sampling of the bottles, a day-to-day effect, the cell constant, the resistance measurement, temperature, and carbon dioxide dissolution. The value of u_c has been multiplied by 2.0, which is the coverage factor corresponding to approximately 95 % confidence based on greater than 1 000 overall effective degrees of freedom.

The original certified value has been revised to the above certified value to account for issues involving the cell calibration. The above value is effective immediately.

Expiration of Certification: The certification of SRM 3192 Lot No. 031121 is valid, within the measurement uncertainty specified, until **25 November 2005**, provided the SRM is handled in accordance with instructions given in this certificate (see "Instructions for Use"). This certification is nullified if the SRM is damaged, contaminated, or otherwise modified.

This SRM was prepared and analyzed by R.H. Shreiner of the NIST Analytical Chemistry Division.

Willie E. May, Chief
Analytical Chemistry Division

Gaithersburg, MD 20899
Certificate Issue Date: 18 May 2004
See Certificate Revision History on Last Page

Robert L. Watters, Jr., Acting Chief
Measurement Services Division

Statistical consultation was provided by W.F. Guthrie of the NIST Statistical Engineering Division.

¹Certain commercial equipment, instruments, or materials are identified in this certificate in order to specify adequately the experimental procedure. Such identification does not imply recommendation or endorsement by the National Institute of Standards and Technology, nor does it imply that the materials or equipment identified are necessarily the best available for the purpose.

The support aspects involved with the preparation, certification, and issuance of this SRM were coordinated through the NIST Standard Reference Materials Program by C.S. Davis of the Measurement Services Division.

Maintenance of Certification: NIST will monitor representative solutions from this SRM lot over the period of its certification. If substantive changes occur that affect the certification before the expiration of certification, NIST will notify the purchaser. Registration (see attached sheet) will facilitate notification.

Conductivity is strongly influenced by temperature, and for this solution, the temperature coefficient at 25 °C is approximately 2 % per °C [4]. The certified value and its uncertainty were determined with the temperature at 25.000 °C \pm 0.004 °C.

INSTRUCTIONS FOR USE

The SRM solution should be kept in the unopened ampoule and stored under normal laboratory conditions, away from acid fumes, nitrogen oxides, and sulfur dioxide. Each ampoule should be treated as a single use standard. This certification is valid only for ampoules that are used immediately after they are opened. The solution should be used immediately after the ampoule is opened to avoid evaporation of the solution being measured.

REFERENCES

- [1] Jameel, R.H.; Wu, Y.C.; Pratt, K.W.; *Primary Standards and Standard Reference Materials for Electrolytic Conductivity*; NIST Special Publication 260-142; U.S. Government Office: Washington, DC (2000).
- [2] Wu, Y.C.; Pratt, K.W.; Koch, W.F.; *Determination of the Absolute Specific Conductance of Primary Standard KCl Solutions*; J. Solution Chem., Vol. 18, p. 515 (1989).
- [3] ISO; *Guide to the Expression of Uncertainty in Measurement*; ISBN 92-67-10188-9, 1st ed., International Organization for Standardization: Geneva, Switzerland (1993); see also Taylor, B.N.; Kuyatt, C.E.; *Guidelines for Evaluating and Expressing the Uncertainty of NIST Measurement Results*; NIST Technical Note 1297; U.S. Government Printing Office: Washington, DC (1994); available at <http://physics.nist.gov/Pubs/>.
- [4] Robinson, R.A.; Stokes, R.H.; *Electrolyte Solutions*; 2nd ed., Butterworths: London (1959).

Certificate Revision Date History: 18 May 2004 (This technical revision reports a change in the certified value and uncertainty); 24 February 2004 (Original certificate date).

Users of this SRM should ensure that the certificate in their possession is current. This can be accomplished by contacting the SRM Program at: telephone (301) 975-6776; fax (301) 926-4751; e-mail srminfo@nist.gov; or via the Internet at <http://www.nist.gov/srm>.